



HP4Q60CT

Three quadrant triacs

HAOPIN MICROELECTRONICS CO.,LTD.

Description

Passivated high commutation triacs in a plastic envelope intended for use in circuits where high static and dynamic dV/dt and high di/dt can occur. These devices will commutate the full rated ms current at the maximum rated junction temperature without the aid of a snubber.

| Symbol | Simplified outline |
|--------|----------------------|
| | |
| Pin | Description |
| 1 | Main terminal 1 (T1) |
| 2 | Main terminal 2 (T2) |
| 3 | gate (G) |
| TAB | Main terminal 2(T2) |

Applications:

- ◆ Motor control
- ◆ Industrial and domestic lighting
- ◆ Heating
- ◆ Static switching

Features

- ◆ Blocking voltage to 600 V
- ◆ On-state RMS current to 4 A

| SYMBOL | PARAMETER | Value | Unit |
|---------------------|---|-------|------|
| V_{DRM} | Repetitive peak off-state voltages | 600 | V |
| $I_T \text{ (RMS)}$ | RMS on-state current (full sine wave) | 4 | A |
| I_{TSM} | Non-repetitive peak on-state current (full cycle, T_j initial=25°C) | 30 | A |

| SYMBOL | PARAMETER | CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------|----------------------|----------------------|-----|-----|-----|------|
| $R_{th(j-c)}$ | Junction to case(AC) | | - | 2.6 | - | °C/W |
| $R_{th(j-a)}$ | Junction to ambient | $s=0.5 \text{ cm}^2$ | - | 70 | - | °C/W |



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Limiting values in accordance with the Maximum system(IEC 134)

| SYMBOL | PARAMETER | CONDITIONS | MIN | MAX | UNIT |
|--------------|---|--|-----|-----|------------|
| V_{DRM} | Repetitive peak off-state Voltages | | - | 600 | V |
| $I_{T(RMS)}$ | RMS on-state current Full sine wave | $T_c=110^\circ C$ | - | 4 | A |
| I^2t | I^2t value for fusing | $T_p=10ms$ | - | 5.1 | A^2s |
| DI/dt | Critical rate of rise of on-state current $I_g=2 \times I_{GT}, t_r \leq 100 \text{ ns}$ | $F=120\text{Hz} \quad T_j=125^\circ C$ | - | 50 | $A/\mu s$ |
| I_{GM} | Peak gate current | $T_p=20 \mu s \quad T_j=125^\circ C$ | - | 4 | A |
| V_{GD} | | $V_D=V_{DRM}; R_L=33k\Omega \quad T_j=125^\circ C$ | 0.2 | - | V |
| V_{GT} | | $V_D=12V; R_i=30\Omega$ | - | 1.3 | V |
| $P_{G(AV)}$ | Average gate power | $T_j=125^\circ C$ | - | 1 | W |
| T_{stg} | Storage temperature | | -40 | 150 | $^\circ C$ |
| T_j | Operating junction Temperature range | | -40 | 125 | $^\circ C$ |

$T_j=25^\circ C$ unless otherwise stated

| SYMBOL | PARAMETER | CONDITIONS | MIN | TYP | MAX | UNIT |
|------------------------|-----------------------------------|---------------------------------------|-------------|-----|--------|---------------|
| Static characteristics | | | | | | |
| I_{GT} | Gate trigger current | $V_D=12V; R_L=30 \Omega$ | I-II-III | - | - | 10 mA |
| I_L | Latching current | $I_g=1.2I_{GT}$ | I-III II | - | - | 10 15 mA |
| I_{DRM} I_{RRM} | $V_{DRM}=V_{RRM}$ | $T_j=25^\circ C$ $T_j=125^\circ C$ | - | - | 5 1 | μA mA |
| I_H | Holding current | $I_T=100mA$ | - | - | 10 | mA |
| V_{TM} | $I_{TM}=5.5A \quad t_p=380 \mu s$ | $T_j=25^\circ C$ | - | - | 1.6 | V |
| V_{To} | Threshold voltage | $T_j=125^\circ C$ | - | - | 0.9 | V |
| R_D | Dynamic resistance | $T_j=125^\circ C$ | - | - | 120 | $M\Omega$ |

Dynamic Characteristics

| | | | | | | |
|------------|--|---|------------|---|---|-----------|
| D_V/dt | Critical rate of rise of Off-state voltage | $V_D=67\% V_{DRM}$ gate open; $T_j=125^\circ C$; | 20 | - | - | $V/\mu s$ |
| $(dI/dt)c$ | | $(dV/dt)c=0.1V/\mu s \quad T_j=125^\circ C$ $(dV/dt)c=10V/\mu s \quad T_j=125^\circ C$ | 1.8 0.9 | - | - | A/ms |

Description

Fig. 1: Maximum power dissipation versus RMS on-state current (full cycle).

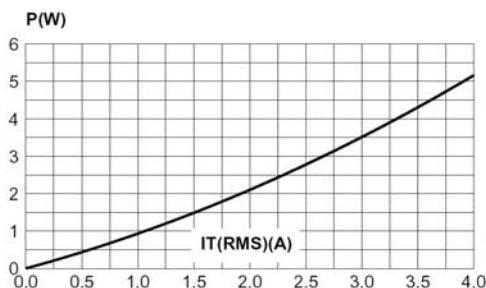


Fig. 2-1: RMS on-state current case versus temperature (full cycle).

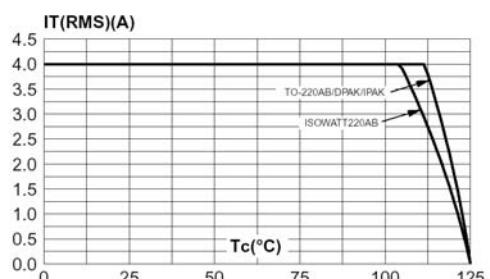


Fig. 2-2: RMS on-state current versus ambient temperature (printed circuit FR4, copper thickness: 35µm), full cycle.

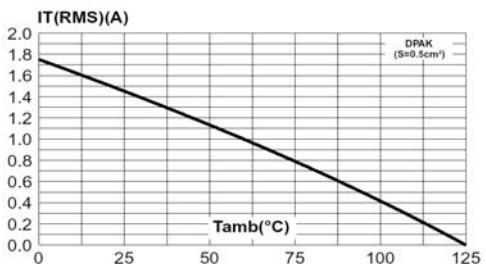


Fig. 3: Relative variation of thermal impedance versus pulse duration.

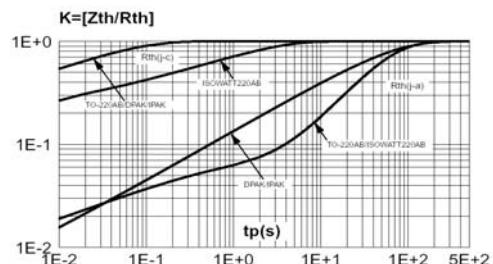


Fig. 4: Relative variation of gate trigger current, holding current and latching current versus junction temperature (typical values).

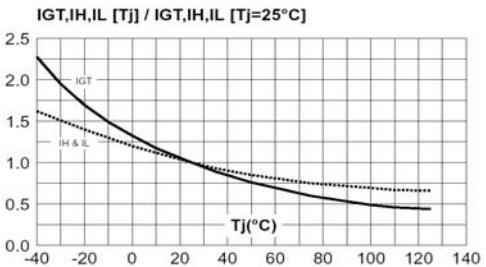
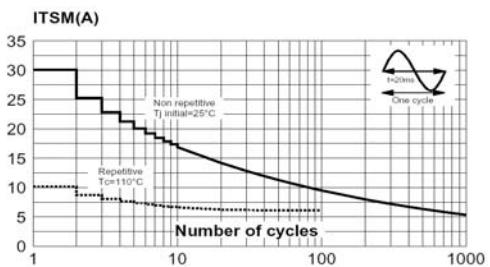


Fig. 5: Surge peak on-state current versus number of cycles.



Description

Fig. 6: Non-repetitive surge peak on-state current for a sinusoidal pulse with width $t_p < 10\text{ms}$, and corresponding value of I^2t .

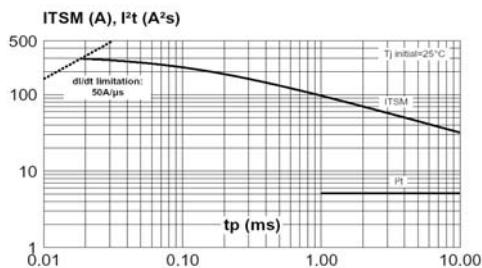


Fig. 7: On-state characteristics (maximum values).

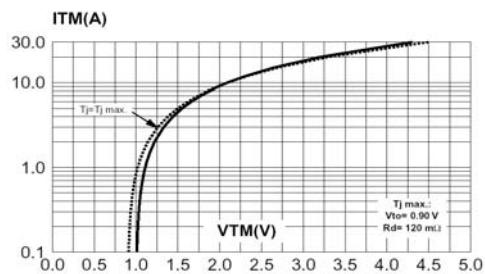


Fig. 8: Relative variation of critical rate of decrease of main current versus $(dV/dt)c$ (typical values).

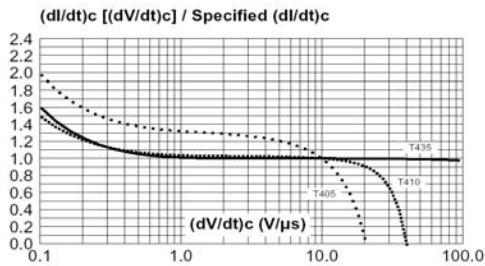


Fig. 9: Relative variation of critical rate of decrease of main current versus junction temperature.

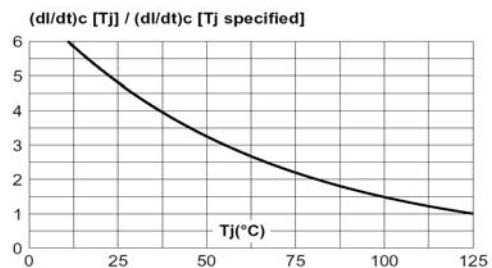
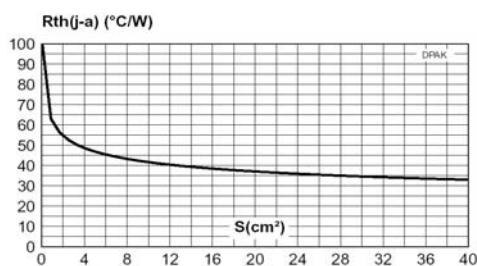


Fig. 10: DPAK thermal resistance junction to ambient versus copper surface under tab (printed circuit board FR4, copper thickness: 35μm).





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MECHANICAL DATA

Dimensions in mm

Net Mass: 0.8 g

SOT-82

